NE556, SA556, SE556, SE556C DUAL PRECISION TIMERS

SLFS023A - APRIL 1978 - REVISED OCTOBER 1992

- Two Precision Timing Circuits per Package
- Astable or Monostable Operation
- TTL-Compatible Output Can Sink or Source Up to 150 mA
- Active Pullup or Pulldown
- Designed to be Interchangeable With Signetics SE556, SE556C, SA556, NE556

applications

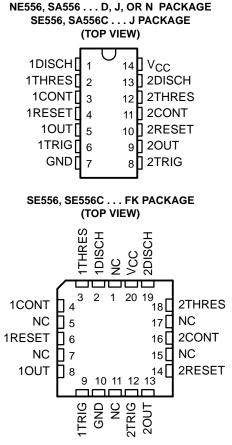
Precision Timer From Microseconds to Hours Pulse-Shaping Clrcuit Missing-Pulse Detector Tone-Burst Generator Pulse-Width Modulator Pulse-Position Modulator Sequential Timer Pulse Generator Frequency Divider Application Timer Industrial Controls Touch-Tone Encoder

SE556C FROM TI IS NOT RECOMMENDED FOR NEW DESIGNS

description

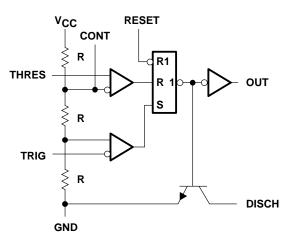
These devices provide two monolithic, independent timing circuits of the NE555, SA555, SE555, or SE555C type in each package. These circuits can be operated in the astable or the monostable mode with external resistor-capacitor timing control. The basic timing provided by the RC time constant may be actively controlled by modulating the bias of the control voltage input.

The threshold and trigger levels are normally two-thirds and one-third respectively of V_{CC} . These levels can be altered by use of the control voltage terminal. When the trigger input falls below trigger level, the flip-flop is set and the output goes high. If the trigger input is above the trigger level and the threshold input is above the threshold level, the flip-flop is reset and the output is low. The reset input can override all other inputs and can be used to initiate a new timing cycle. When the reset input goes low, the flip-flop is reset and the output is low, a low impedance path is provided between the discharge terminal and ground.



NC - No internal connection

functional block diagram (each timer)



RESET can override TRIG, which can override THRES.

PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



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description (continued)

The NE556 is characterized for operation from 0°C to 70°C. The SA556 is characterized for operation from -40°C to 85°C, and the SE556 and SE556C are characterized for operation over the full military range of -55°C to 125°C.

			PACKA	GE	
T _A RANGE	V _{thres} max V _{CC} = 15 V	SMALL OUTLINE (D)	CHIP OUTLINE (FK)	CERAMIC DIP (J)	PLASTIC DIP (N)
0°C to 70°C	11.2 V	NE556D		NE556J	
– 40°C to 85°C	11.2 V	SA556D		SA556J	SA556N
– 55°C to 125°C	10.6 V 11.2 V		SE556FK SE556CFK		

AVAILABLE OPTIONS

The D package is available taped and reeled. Add the suffix R to the devicetype (e.g., NE556DR).

	FUNCTION TABLE								
RESET	TRIGGER VOLTAGE [†]	THRESHOLD VOLTAGE [†]	OUTPUT	DISCHARGE SWITCH					
Low	Irrelevant	Irrelevant	Low	On					
High	< 1/3 V _{DD}	Irrelevant	High	Off					
High	> 1/3 V _{DD}	> 2/3 V _{DD}	Low	On					
High	> 1/3 V _{DD}	> 2/3 V _{DD}	As previously established						

FUNCTION TABLE

[†] Voltage levels shown are nominal.

absollute maximum ratings over operating free-air temperature range (unless otherwise noted)[‡]

Supply voltage, V _{CC} (see Note 1) Input voltage (CONT, RESET, THRES, and TRIG)	
Output current	
Continuous total dissipation	See Dissipation Rating Table
Operating free-air temperature range: NE556	0°C to 70°C
SA556	40°C to 85°C
SE556, SE556C	55°C to 125°C
Storage temperature range	65°C to 150°C
Case temperature for 60 seconds: FK package	260°C
Lead temperature 1,6 mm (1/16 inch) from case for 60 seconds: J package	300°C
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds: D or N pac	kage 260°C

[‡] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: All voltage values are with respect to network ground terminal.

DISSIPATION RATING TABLE									
PACKAGE	TA ≤ 25°C POWER RATING	DERATING FACTOR ABOVE T _A = 25°C	T _A = 70°C POWER RATING	T _A = 85°C POWER RATING	T _A = 125°C POWER RATING				
D	950 mW	7.6 mW/°C	608 mW	494 mW	N/A				
FK	1375 mW	11.0 mW/°C	880 mW	715 mW	275 mW				
J (NE556, SA556)	1025 mW	8.2 mW/°C	656 mW	533 mW	N/A				
J (SE556, SE556C)	1375 mW	11.0 mW/°C	880 mW	715 mW	275 mW				
N	1575 mW	12.6 mW/°C	1008 mW	891 mW	N/A				



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recommended operating conditions

	NE556		SA556		SE556		SE556C		
	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	UNIT
Supply voltage, V _{CC}	4.5	16	4.5	16	4.5	18	4.5	16	V
Input voltage (CONT, RESET, THRES, and TRIG), VI		Vcc		Vcc		VCC		VCC	V
Output current, IO		±200		±200		±200		±200	mA
Operating free-air temperature, T _A	0	70	-40	85	-55	125	-55	125	°C

electrical characteristics, V_{CC} = 5 V to 15 V, T_A = 25°C (unless otherwise noted)

	PARAMETER	TEST CONDITIONS		NE556, SA556, SE556C			SE556			UNIT
				MIN	TYP	MAX	MIN	TYP	MAX	
Vт	Threshold voltage level	V _{CC} = 15 V		8.8	10	11.2	9.4	10	10.6	v
۷I	Threshold voltage level	$V_{CC} = 5 V$		2.4	3.3	4.2	2.7	3.3	4	v
ΙŢ	Threshold current (see Note 2)				30	250		30	250	nA
\/==\-	Trigger voltage level	V _{CC} = 15 V		4.5	5	5.6	4.8	5	5.2	v
VTRIG	ringger voltage level	V _{CC} = 5 V		1.1	1.67	2.2	1.45	1.67	1.9	v
ITRIG	Trigger current	TRIG at 0 V			0.5	2		0.5	0.9	μA
VRESET	Reset voltage level			0.3	0.7	1	0.3	0.7	1	V
	Reset current	RESET at VC	C		0.1	0.4		0.1	0.4	
IRESET	Reset current	RESET at 0	/		-0.4	-1.5		-0.4	-1	mA
IDISCH	Discharge switch off-state current				20	100		20	100	nA
VCONT Control voltage (c		V _{CC} = 15 V V _{CC} = 5 V		9	10	11	9.6	10	10.4	V
	Control voltage (open circuit)			2.6	3.3	4	2.9	3.3	3.8	
	Low-level output voltage		I _{OL} = 10 mA		0.1	0.25		0.1	0.15	-
		V _{CC} = 15 V	I _{OL} = 50 mA		0.4	0.75		0.4	0.5	
M			I _{OL} = 100 mA		2	2.5		2	2.2	
VOL			I _{OL} = 200 mA		2.5			2.5		
			I _{OL} = 5 mA		0.1	0.25		0.1	0.15	
		VCC = 5 V	I _{OL} = 8 mA		0.15	0.3		0.15	0.25	
			$I_{OH} = -100 \text{ mA}$	12.75	13.3		13	13.3		
VOH	High-level output voltage	V _{CC} = 15 V	$I_{OH} = -200 \text{ mA}$		12.5			12.5		V
		V _{CC} = 5 V	I _{OH} = -100 mA	2.75	3.3		3	3.3		
		Output high, No Load	V _{CC} = 15 V		20	30		20	24	nA
1	Supply surrent		V _{CC} = 5 V		6	12		6	10	
ICC	Supply current	Output high, No load	V _{CC} = 15 V		18	26		18	20	
			V _{CC} = 5 V		4	10		4	8	

NOTE 2: This parameter influences the maximum value of the timing resistors R_A and R_B in the circuit of Figure 1. For example, when $V_{CC} = 5 \text{ V}$, the maximum value is $R = R_A + R_B \approx 3.4 \text{ M}\Omega$, and for $V_{CC} = 15 \text{ V}$, the maximum value is $\approx 10 \text{ M}\Omega$.



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operating characteristics, V_{CC} = 5 V and 15 V

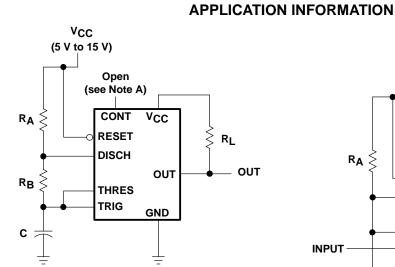
PARAMETER		TEST CONDITIONS [†]	NE556, SA556, SE556C			SE556			UNIT	
		CONDITIONS	MIN	TYP	MAX	MIN	TYP	MAX		
	Each timer, monostable§			1	3		0.5	1.5		
Initial error of timing interval‡	Each timer, astable¶	T _A = 25°C		2.25%			1.5%			
	Timer 1 — Timer 2			±1			±0.5			
_	Each timer, monostable§	$T_A = MIN$ to MAX		50			30	100		
Temperature coefficient of timing interval	Each timer, astable¶			150			90		ppm/°C	
	Timer 1 — Timer 2			±10			±10]	
	Each timer, monostable§			0.1	0.5		0.05	0.2		
Supply voltage sensitivity of timing interval	Each timer, astable¶	T _A = 25°C		0.3			0.15		%/V	
	Timer 1 — Timer 2			±0.2			±0.1			
Output pulse rise time		C _L = 15 pF,		100	300		100	200		
Output pulse fall time		$T_{A} = 25^{\circ}C$		100	300		100	200	ns	

[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

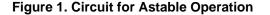
[‡] Timing interval error is defined as the difference between the measured value and the average value of a random sample from each process run.

§ Values specified are for a device in a monostable circuit similar to Figure 2, with component values as follow: R_A = 2 kΩ to 100 kΩ, C = 0.1μF.

I Values specified are for a device in an astable circuit similar to Figure 1, with component values as follow: $R_A = 1 k\Omega$ to 100 k Ω , $C = 0.1 \mu F$.



NOTE A: Bypassing the control voltage input to ground with a capacitor may improve operation. This should be evaluated for individual applications.



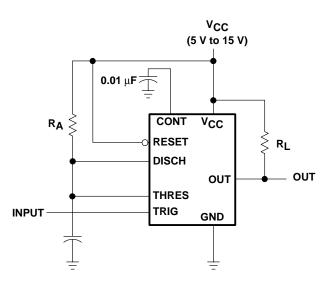


Figure 2. Circuit for Monostable Operation



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